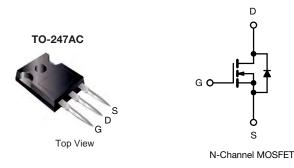


IXGH32N60A-VB Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				



FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \degree C$, unless otherwise noted)								
PARAMETER			LIMIT	UNIT				
Drain-Source Voltage			650	V				
Gate-Source Voltage			± 30	v				
V _{GS} at 10 V	T _C = 25 °C	I _D	20					
	T _C = 100 °C		13	А				
Pulsed Drain Current ^a			53					
Linear Derating Factor			1.7	W/°C				
Single Pulse Avalanche Energy ^b			367	mJ				
Maximum Power Dissipation			P _D 208					
Operating Junction and Storage Temperature Range			-55 to +150	°C				
T _J = 125 °C		d\//dt	37	V/ns				
Reverse Diode dV/dt ^d			31	v/ns				
for 10 s			300	°C				
	V _{GS} at 10 V e T _J = -	$V_{GS} \text{ at } 10 \text{ V} \qquad \frac{T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$ $T_{J} = 125 \text{ °C}$	$\begin{tabular}{ c c c c c } & SYMBOL & & & & & & & & & & & & & & & & & & &$	$\begin{tabular}{ c c c c c } \hline SYMBOL & LIMIT \\ \hline V_{DS} & 650 \\ \hline V_{GS} & \pm 30 \\ \hline V_{GS} at 10 \ V & \hline T_C = 25 \ ^{\circ}C & $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



PARAMETER SYMBOL TYP. MAX. UNIT Maximum Junction-to-Case (Drain) R _{InJA} - 62 -C/W SPECIFICATIONS (T_j = 25 °C, unless otherwise noted) SPECIFICATIONS (T_j = 25 °C, unless otherwise noted) Min. TYP. MAX. UNIT SpecificAtions (C_j = 25 °C, unless otherwise noted) SPECIFICATIONS (T_j = 25 °C, lp = 1 mA 650 - - V/C Gate-Source Breakdown Voltage Vogs Vogs = 0 V, lp = 250 µA 650 - - V/C Gate-Source Threshold Voltage (N) VogsPU Reference to 25 °C, lp = 1 mA 0.67 - V/C Gate-Source Threshold Voltage (N) VogsPU VogsPU - - ± 100 nA Vogs Temperature Coefficient ΔVogSVI Vogs = 20 V, Vogs = 0 V - - ± 100 nA Jack-Source Insekold Voltage (N) VogsPU Vogs = 0 V - - 1 µA Zero Gate Voltage Drain Current Iogs Vogs = 0 V Vogs = 0 V, Vog = 0 V, Vog = 0 V, Vog = 0 V, Vog = 0 V	THERMAL RESISTANCE RAT	INGS								
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP. MAX.			UNIT				
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}	- 62							
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Case (Drain)		-							
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$$		·	•							
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$$	SPECIFICATIONS (T _J = 25 °C, u	unless otherwi	ise noted)							
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$				T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Static	1								
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	650	-	-	V	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Oata Cauraa Laalua aa				-	-	± 100	nA		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage			V	-	-	± 1	μA		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zaro Cato Voltago Drain Current		V _{DS} =			-	-	1		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate voltage Drain Current	IDSS	V _{DS} = 520 \				-	500	μA	
	Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$		_D = 11 A	-	0.19	-	Ω	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S	
Utput CapacitanceCossVos = 0V, r = 1 MHz-105-Reverse Transfer CapacitanceCress Γ_{rss} Γ_{rss} -4Effective Output Capacitance, Energy Related aCo(er) Γ_{rss} Γ_{rss} -84Effective Output Capacitance, Time Related b $C_{o(tr)}$ $V_{DS} = 0 V$ to 520 V, $V_{GS} = 0 V$ -84Total Gate Charge Q_g Q_g Γ_{rss} Γ_{rss} Γ_{rss} -114-nCGate-Source Charge Q_{gd} $V_{GS} = 10 V$ $I_D = 11 A$, $V_{DS} = 520 V$ -114-nCGate-Drain Charge Q_{gd} $V_{GS} = 10 V$ $I_D = 11 A$, $V_{DS} = 520 V$ -144-nCGate-Drain Charge Q_{gd} $V_{GS} = 10 V$ $I_D = 11 A$, $V_{DS} = 520 V$ -144-nCTurn-On Delay Time $t_{d(on)}$ $V_{CS} = 10 V$ $V_{CS} = 10 V$, $R_g = 9.1 \Omega$ -2244-Fail Time t_f $V_{CS} = 10 V$, $R_g = 9.1 \Omega$ -681020Fail Time t_f T_g T_g -621020Pulsed Diode Forward Current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode-0.91.2VPulsed Diode Forward Voltage V_{SD} $T_J = 25 °C$, $I_S = 11 A$, $V_{GS} = 0 V$ -0.91.2VReverse Recovery	Dynamic	-	-							
$ \begin{array}{ c c c c c c c } \hline Output Capacitance & C_{oss} & V_{DS} = 100 \ V, & - & 105 & - & - & 4 & - & - & - & 4 & - & - & -$	Input Capacitance	C _{iss}	V _{DS} = 100 V,		-	2322	-	pF		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}			-	105	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}			-	4	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $			V_{DS} = 0 V to 520 V, V_{GS} = 0 V		-	84	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C _{o(tr)}			-	293	-			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg		V _{GS} = 10 V I _D = 11		-	71	106	nC	
$ \begin{array}{c c c c c c c c c } \hline Turn-On Delay Time & t_{d(on)} & & & & & & & & & & & & & & & & & & &$	Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$			-	14	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge	Q _{gd}				-	33	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-On Delay Time	t _{d(on)}				-	22	44		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r	V _{DD} =			-	34	68	ns	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-Off Delay Time	t _{d(off)}	V _{GS} :			-	68	102		
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMIsMT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VDiode Forward VoltageV_{SDT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VReverse Recovery TimetrrT_J = 25 °C, I_F = I_S = 11 A, dl/dt = 100 A/µs, V_R = 25 V-160-ns	Fall Time	t _f			-	42	84			
	Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Body Diode Characterist	cs								
Pulsed Diode Forward CurrentIsmIntegra reverse p - n junction diode53Diode Forward Voltage V_{SD} $T_J = 25 ^{\circ}C$, $I_S = 11 A$, $V_{GS} = 0 V$ -0.91.2VReverse Recovery Time t_{rr} $T_J = 25 ^{\circ}C$, $I_F = I_S = 11 A$, dl/dt = 100 A/µs, $V_R = 25 V$ -160-ns	Continuous Source-Drain Diode Current	I _S	showing the integral reverse		-	-	21	A		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Pulsed Diode Forward Current	I _{SM}			-	-	53			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V		
Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C, I_F = I_S = 11 \ A,$ dl/dt = 100 A/µs, $V_B = 25 \ V$ -1.2-µC	Reverse Recovery Time		T _J = 25 °C, I _F = I _S = 11 A,		-	160	-	ns		
αι/dt = 100 A/μS, VR = 23 V	Reverse Recovery Charge				-	1.2	-	μC		
	Reverse Recovery Current		u/ut =	$ai/at = 100 \text{ A}/\mu\text{s}, \text{ V}_{\text{R}} = 25 \text{ V}$		-	14	-		

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

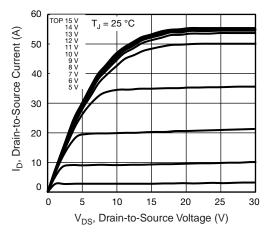


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

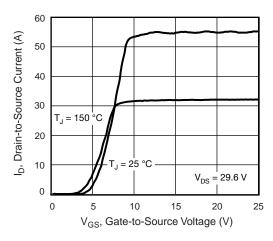


Fig. 3 - Typical Transfer Characteristics

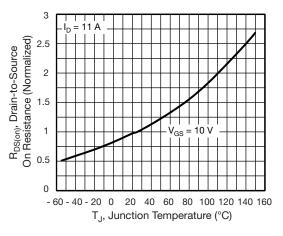


Fig. 4 - Normalized On-Resistance vs. Temperature

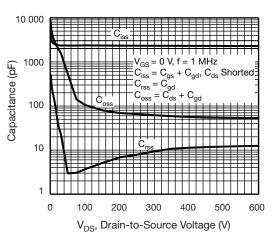


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

IXGH32N60A-VB



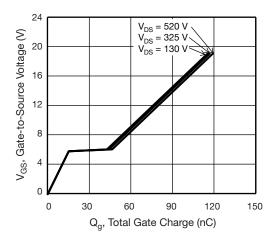


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

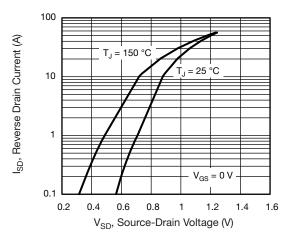


Fig. 8 - Typical Source-Drain Diode Forward Voltage

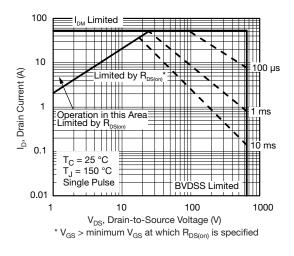


Fig. 9 - Maximum Safe Operating Area

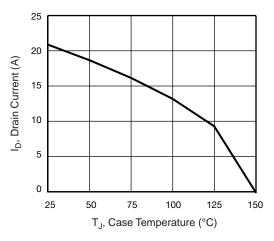


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



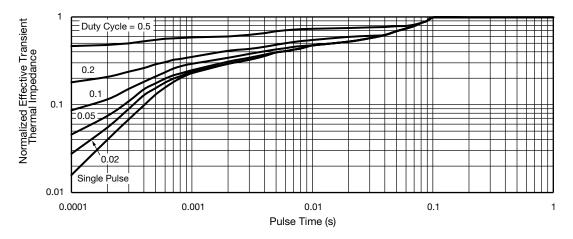


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

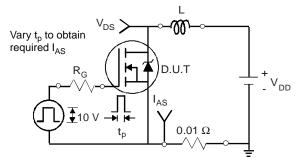


Fig. 15 - Unclamped Inductive Test Circuit

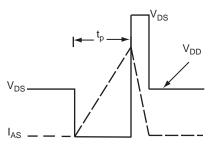


Fig. 16 - Unclamped Inductive Waveforms

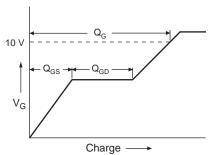
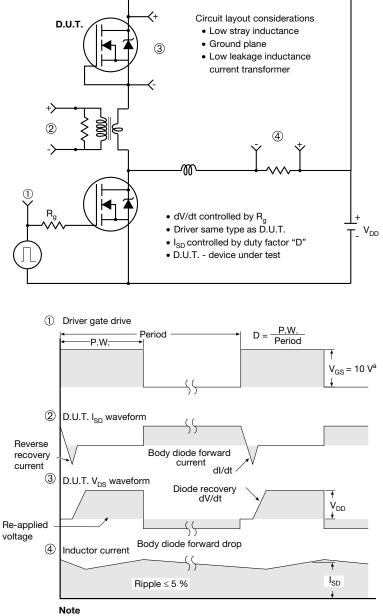


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



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